# Principal Component Analysis

January 21, 2022

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- Features: source of information.
- As the number of variables rises, dim(V) increases.
- Two complementary hurdles stem from-
  - 1. # samples constant.
  - 2. Density of the samples constant.

- 1. Hughes phenomenon or Peaking phenomenon.
  - Initially accuracy increases with increasing number of features.

• 
$$L_2^n := \sum_{i=1}^n \sqrt{x_i^2} \ge \sum_{i=1}^{n-1} \sqrt{x_i^2} = L_2^{n-1}$$

 The data points become sparse and a pattern could hardly be detected in higher dimensions.

Abstract—The overall mean recognition probability (mean accuracy) of a pattern classifier is calculated and numerically plotted as a function of the pattern measurement complexity n and design data set size m. Utilized is the well-known probabilistic model of a two-class, discrete-measurement pattern environment (ao Gaussian or statistical independence assumptions are made). The minimum-error recognition rule (Bayes) is used, with the unknown pattern environment probabilities estimated from the data relative frequencies. In calculating the mean accuracy over all such environments, only three parameters remain in the final equation: n, m, and the origin or bability n, of either of the pattern classes.

With a fixed design pattern sample, recognition accuracy can first increase as the number of measurements made on a pattern

increases, but decay with measurement complexity higher than some optimum value. Graphs of the mean accuracy exhibit both an optimal and a maximum acceptable value of n for fixed m and potable. A four-place tabulation of the optimum n and maximum mean accracy values is given for equally likely classes and m ranging from 22 to 1000.

The penalty exacted for the generality of the analysis is the use of the mean accuracy itself as a recognizer optimality criterion. Namely, one necessarily always has some particular recognition problem at hand whose Bayes accuracy will be higher or lower than the mean overall recognition problems having fixed n, m, and p,... m, and p...

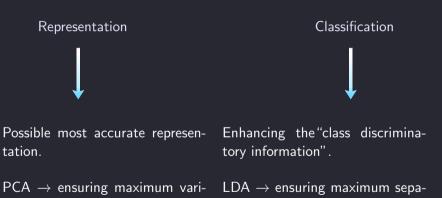
- 2. Computational cost and over-fitting
  - m data points/ dimension  $\implies m^{\dim(V)}$
  - Computational cost would rise exponentially.
  - Huge training set  $\implies$  overly *intricate* patterns.

The way out: reducing # dimensions

- Feature selection:
  - $f_{S}: \mathbb{R}^{n} \mapsto \mathbb{R}^{m}$
  - $\mathbf{v} = \{v_1, \ldots, v_n\} \in \mathbb{R}^n$
  - $f_{S}(v) = \{v_{i1}, \ldots, v_{im} | v_{ij} \in v, \forall j\}$
- Feature extraction:
  - $\blacksquare f_F: \mathbb{R}^n \mapsto \mathbb{R}^m$
  - An optimal mapping must not increase  $P[\epsilon]$ .
  - No systematic way to find an optimum nonlinear  $f_E$ .

### Dimensionality reduction

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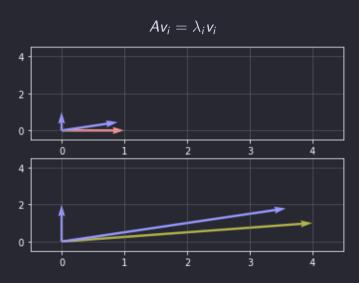
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### The PCA Algo

#### Algorithm:

- 1. Given a  $p \times n$  data-set: N samples with n features.
- 2. Center the data-set.
- 3. Calculate the co-variance matrix  $\Sigma_n$ .
- 4. Calculate the eigenvalues  $(\lambda_i)$  and the corresponding eigenvectors  $(v_i)$  of  $\Sigma$ .
- 5. Arrange  $(\lambda_i, v_i)$  following the order of  $\{\lambda_i | \lambda_{i+1} < \lambda_i\}$ .
- 6. First *m* eigenvectors correspond to the first *m* PA.
- 7. "Rotate" the data considering  $\{v_{i1}, \ldots, v_{im}\}$  as the basis.

## Detour: Eigen-world



### Detour: Eigenbasis

```
Say, A is symmetric

Let \{v_1, \ldots, v_k\} correspond to \{\lambda_1, \ldots, \lambda_k\}

Claim: \{v_1, \ldots, v_k\} is LI

Suppose not!

v_j = \sum_{i=1}^{j-1} \alpha_i v_i

\Rightarrow \lambda_j v_j = \sum_{i=1}^{j-1} \alpha_i \lambda_i v_i

\Rightarrow \sum_{i=1}^{j-1} \alpha_i (\lambda_j - \lambda_i) v_i = 0

\lambda_i, \lambda_i are distinct by construction.
```

### Detour: Eigenbasis

Claim: 
$$v_i \perp v_j, \forall i, j$$
  
 $Av_i = \lambda_i v_i$   
 $\implies v_i^t A^t = \lambda_i v_i^t$   
 $\implies v_i^t A v_j = \lambda_i v_i^t v_j$   
 $\implies v_i^t \lambda_j v_j = \lambda_i v_i^t v_j$   
 $\lambda_i, \lambda_j$  are distinct by construction.  
 $\therefore v_i^t v_j = 0$ 

### Detour: Eigenbasis

#### Real spectral theorem:

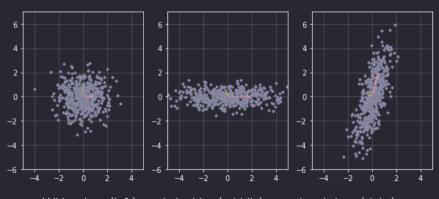
$$F = \mathbb{R}, T \in \mathcal{L}(V)$$
. Then-  
  $T = T^* \Leftrightarrow V$  has an orthonormal basis consisting of eigenvectors of  $T$ .

 $\Sigma$  is symmetric, hence Hermitian.

How to *understand* the eigen-decomposition of  $\Sigma$  <sup>1</sup>?

- Take a 2D normally distributed data set, with  $\Sigma = I_2$ .
- Intuitively, a tilted, correlated data-set can be created out of it...
  - by scaling and rotation!

<sup>&</sup>lt;sup>1</sup>Inspired by *Understanding the Covariance matrix* by N. Janakiev, 2018



White data (left), scaled white (middle), correlated data (right)

Is it possible to decompose  $\Sigma$  in terms of L and R?

- $\Sigma$  is symmetric  $\implies k = \dim(\mathbb{R}^n)$  where k is # of distinct eigenvectors.
- $\Sigma v_i = \lambda_i v_i, i = 1, \ldots, n$
- Therefore,  $\Sigma V = VL$  where V contains the eigenvectors as columns,  $L = \text{diag}[\lambda_1, \dots, \lambda_n]$
- $\Sigma = VLV^{-1}$ .

- V is orthonormal, hence can be treated as a rotation matrix.
- $\Sigma = VLV^{-1} = RSSR^{-1}$  where  $R = V.S^2 = L$
- $\Sigma = RSSR^{-1} = CC^{t}$  (Cholesky decomposition)
  - $C^t = (RS)^t = S^t R^t = SR^{-1}$
  - $\blacksquare x := \mu + Cu, u \sim \mathcal{N}(0, I)$
  - $\blacksquare E[x] = \mu, E[(x \mu)(x \mu)^t] = \Sigma$

$$S = \begin{pmatrix} 2 & 0 \\ 0 & 0.5 \end{pmatrix}, \ S = \begin{pmatrix} \cos(\theta) & -\sin(\theta) \\ \sin(\theta) & \cos(\theta) \end{pmatrix} \text{ where } \theta = 5\pi/12$$
 
$$\Sigma = \begin{pmatrix} 0.5595 & 1.0793 \\ 1.0793 & 4.1357 \end{pmatrix}$$
 
$$RSSR^{-1} = \begin{pmatrix} 0.5012 & 0.9375 \\ 0.9375 & 3.7488 \end{pmatrix}$$

#### Representation in a low dimensional space

- $x \in \mathbb{R}^n$  and  $\beta := \{\beta_i | i = 1, ..., n\}$  be an orthonormal basis vector.
  - Every inner product space will have an orthonormal basis, constructed via Gram-Schmidt process.
- $x = \sum_{i=1}^{n} x_i \beta_i$
- x can be represented in  $\mathbb{R}^m$  by  $\hat{x} = \sum_{i=1}^m x_i \beta_i + \sum_{i=m+1}^n a_i \beta_i$ .
- Thus,  $\Delta x = x \hat{x} = \sum_{i=m+1}^{n} (x_i a_i) \beta_{i,j}$

#### Estimation of MSE

• 
$$\epsilon := E[\Delta x^2]$$
  

$$= E[\Delta x^t \Delta x]$$
  

$$= E[\sum_{i=m+1}^n \sum_{i=m+1}^n (x_i - a_i)(x_j - a_j)\beta_i^t \beta_j]$$
  

$$= \sum_{i=m+1}^n E[(x_i - a_i)^2]$$

$$\bullet \ \frac{\partial \epsilon}{\partial a_i} = 0 \\
\Longrightarrow \ a_i = E[x_i]$$

#### Estimation of MSE

```
• \epsilon = \sum_{i=m+1}^{n} E[(x_i - E[x_i])^2]

To be noted: x_i = \beta_i^t x

\epsilon = \sum_{i=m+1}^{n} E[(\beta_i^t (x - E[x]))^2]

= \sum_{i=m+1}^{n} E[(\beta_i^t (x - E[x])(\beta_i^t (x - E[x])^t])

= \sum_{i=m+1}^{n} \beta_i^t (x - E[x])(x - E[x])^t \beta_i

= \sum_{i=m+1}^{n} \beta_i^t \sum_i \beta_i
```

### Detour: The Lagrange Multiplier

- $f: D \mapsto \mathbb{R}$  is closed and bounded. Then  $P_1, P_2 \in D$  such that  $\max_{\mathbb{R}} f = f(P_1), \min_{\mathbb{R}} f = f(P_2)$ .
- Constrained optimization: Optimize  $f : \mathbb{R}^n \mapsto \mathbb{R}$  given a *constraint*  $g : \mathbb{R}^n \mapsto \{0\}.$ 
  - $\mathcal{L} := f + \lambda g$  ( $\lambda$  being the Lagrange multiplier)
  - Find  $x \in \mathbb{R}^n$  s.t.  $\mathcal{L}'|_{x} = 0$ . If P is an extremum,  $P \in \{x\}$ .

### Detour: The Lagrange Multiplier

Why should this method work?

- P be an extremum of f.
- $\rho(t) = \langle x(t), y(t), z(t) \rangle$  be any parametric curve on the surface defined by  $\mathcal{S} := (g(x) = 0)$ , passing through  $P = \rho(0)$ .
- h(t) := f(x(t), y(t), z(t))
- h has an extremum at P.
- $h'|_0 = \langle \nabla f|_{\rho(0)}, \rho'(0) \rangle = 0$
- $\nabla f|_P \perp \rho(t)$ , for any  $\rho$ .
- $\nabla g|_P \perp \mathcal{S} \implies \nabla f|_P \parallel \nabla g|_P$

#### Minimizing the MSE

- Constraint:  $\langle \beta_i | \beta_i \rangle = 1$ , as an orthonormal basis is considered.
- $\mathcal{L} = \sum_{i=m+1}^{n} \beta_i^t \sum \beta_i + \sum_{i=m+1}^{n} \lambda_i (\beta_i^t \beta_i 1)$
- $\nabla \mathcal{L} = 0$ 
  - $\frac{\partial \sum_{i=1}^{n} \beta_{i}^{t} \Sigma \beta_{i}}{\partial \beta_{i}} = \frac{\partial \beta_{i}^{t} \Sigma \beta_{i}}{\partial \beta_{i}} = \frac{\partial \left\langle \beta_{i} | \Sigma \beta_{i} \right\rangle}{\beta_{i}} = \left\langle 1 | \Sigma \beta_{i} \right\rangle + \left\langle \beta_{i} | \Sigma \right\rangle = 2\beta_{i}^{t} \Sigma$

  - $\begin{array}{c} \blacksquare \ \, \therefore 2\beta_i^t \Sigma = 2\lambda_i \beta_i^t \\ \Longrightarrow \ \, (\beta_i^t \Sigma)^t = (\lambda \beta_i^t)^t \\ \Longrightarrow \ \, \Sigma \beta_i^t = \lambda_i \beta_i \text{ the necessary condition} \end{array}$

#### Minimizing the MSE

- The necessary condition  $\stackrel{?}{\rightarrow}$  sufficient condition
- Arrange  $\{\lambda_i|i=1,\ldots,n\}\mapsto \{\lambda_{ij}|j=1,\ldots,n,\lambda_{i(j+1)}<\lambda_{ij}\}$
- Consider  $S = \{\lambda_{i(m+1)}, \dots, \lambda_{in}\}$
- S minimizes  $\mathcal{L} = \sum_{i=m+1}^{n} (2\beta_i^t \lambda_i \beta_i \lambda_i) = \sum_{i=m+1}^{n} \lambda_i$ , considering any collection of n-m tuples  $(\lambda_i, \beta_i)$ .

#### An Alternative POV: Maximizing Var

- The implicit goal of PCA is to maximize spread of the data-set.
- Assume y is already mean-deducted  $(y = y_0 E[y_i])$ .
- $\beta = \{\beta_i | i = 1, ..., n\}$  be an orthonormal basis of  $\mathbb{R}^n$  (as before).
- The new data, after relevant projection, is given by  $\langle y^t | \beta_i \rangle \beta_i$ .
- The goal is to maximize  $\sum_{i=1}^{n} \text{Var}[y^t \beta_i]$ .

#### An Alternative POV: Maximizing Var

- $\sum_{i=1}^{n} \text{Var}[y^{t}\beta_{i}]$   $= \sum_{i=1}^{n} E[(y^{t}\beta_{i})^{t}(y^{t}\beta_{i})]$   $= E[y^{t}\beta_{i}] = E[y]^{t}\beta_{i} = 0_{n}$   $= \sum_{i=1}^{n} E[\beta_{i}^{t}yy^{t}\beta_{i}]$   $= \sum_{i=1}^{n} \beta_{i}^{t} E[yy^{t}]\beta_{i} = \sum_{i} \beta_{i}^{t} \Sigma \beta_{i}$
- ullet Define an exact same  ${\cal L}$  to find the exact same set of solutions.
  - To maximize the measure, consider  $S = \{\lambda_{i1}, \dots, \lambda_{im}\}.$

What is the interpretation?

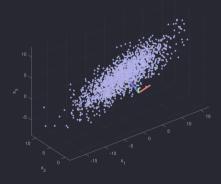
- Estimate  $\Sigma_n$ , calculate its normalized eigenvectors  $\{v_i|i=1,\ldots,n\}$ .
- $\{v_i|i=1,\ldots,n\}\mapsto \{v_{ij}|j=1,\ldots,n\}$  such that  $\{\lambda(v_{ij})\}$  is in decreasing order.
- Say, the intention is to reduce dimension to *m*, from *n*.

#### What is the interpretation?

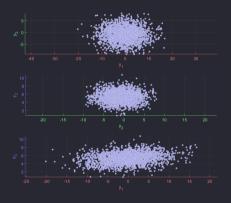
- Consider first *m* eigenvectors from the rearranged set.
  - 1. The rest will minimize the MSE after projecting the data onto the eigenbasis and substituting  $x_i$  with  $E[x_i], \forall i = m+1, \ldots, n$ .
  - 2. Those vectors will maximize the net variance of the projection of each data point *y* onto the eigenbasis.
- This reasoning justifies the PCA algorithm outlined initially.

Data set generated using following parameters:

$$\mu = \begin{pmatrix} 0 \\ 5 \\ 2 \end{pmatrix}, \quad \Sigma = \begin{pmatrix} 25 & -1 & 7 \\ -1 & 4 & -4 \\ 7 & -4 & 10 \end{pmatrix}, \quad n = 2000$$



Distribution of the data set in  $\mathbb{R}^3$ 



Projection onto  $\mathbb{R}^2$ , spanned by any two eigenbasis

### Interpretation of a PCA plot

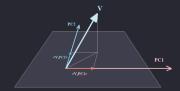
- The dimension is reduced from *n* to *m*.
- Any connection to the original features, however, is lost, in terms of its representation.
- How to bring the original features into the picture?

...Loading and correlation!

#### Interpretation of a PCA plot

#### Loading and correlation

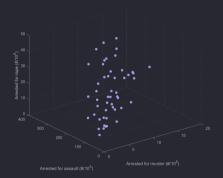
- $v \in \mathbb{R}^n$  and  $PC_1, PC_2$  be first two principal components.
- The goal is to represent v on the plane spanned by  $\{PC_1, PC_2\}$ .
- $\hat{v} = \langle v|PC_1 \rangle PC_1 + \langle v|PC_2 \rangle PC_2 = a_{v,1}PC_1 + a_{v,2}PC_2$ 
  - $\blacksquare$   $a_{v,1}, a_{v,2}$  are the *loadings* for v.



#### Interpretation of a PCA plot

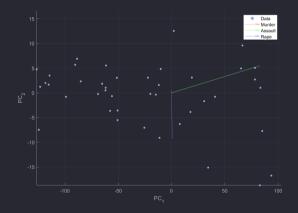
#### Loading and correlation

- $u, v \in \mathbb{R}^n$ , both centered.
- $\sigma_u^2 = \frac{1}{n-1} \sum_{i=1}^n u_i^2 = \frac{1}{n-1} ||u||^2$
- $\sigma_{uv} = \frac{1}{n-1} \sum_{i=1}^n u_i v_i = \frac{1}{n-1} \langle u | v \rangle$
- $\rho_{uv} = \frac{\sigma_{uv}}{\sigma_u \sigma_v} = \frac{\langle u | v \rangle}{||u||||v||} = \cos \phi$
- More interestingly,  $a_{v,i} = \langle v | PC_i \rangle = \rho_{v,PC_i}$  when v as well as  $PC_i$  is standardized.
  - v can indeed be standardized when the features are measured in different units.

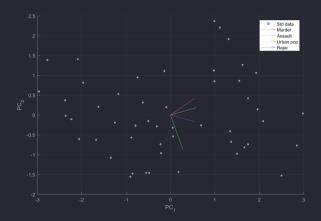


Scatter representation of usArrest data-set <sup>2</sup>, wrt 3 dimensions

<sup>&</sup>lt;sup>2</sup>https://www.picostat.com/dataset/usarrests



Two PC representation: original features to be noted



Two PC representation: original features to be noted

### Proportion of Variance Explained

• 
$$PVE_i := \frac{\mathsf{Var}((V^tX)_i)}{\sum_{j=1}^p \mathsf{Var}(X_j)}$$

• For the last representation, PVE = (0.62, 0.25, 0.09, 0.04)